Exploring the Structural Stability, Electronic and Thermal Attributes of

synthetic 2D Materials and their Heterostructures

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ABSTRACT

Based on first-principles calculations, we have investigated the structural stability, electronic

structures, and thermal properties of the monolayer XSi₂N₄ (X= Ti, Mo, W) and their lateral (LH)

and vertical heterostructures (VH). We find that these heterostructures are energetically and

dynamically stable due to high cohesive and binding energies, and no negative frequencies in the

phonon spectra. The XSi₂N₄ (X= Ti, Mo, W) monolayers, the TiSi₂N₄/MoSi₂N₄-LH,

MoSi₂N₄/WSi₂N₄-LH, and MoSi₂N₄/WSi₂N₄-VH possess a semiconducting nature with an indirect

band gap ranging from 0.30 to 2.60 eV. At room temperature, the C_v values are found to be between

100 and 416 JK⁻¹mol⁻¹ for the monolayers and their heterostructures, suggesting the better ability

to retain heat with respect to transition metal dichalcogenides. Our study unveils the excellent

attributes of XSi₂N₄ 2D monolayers and their heterostructures, proposing them as potential

candidates in nanoelectronics and thermoelectric applications.

1. Introduction

Due to the monolayer limit, the two-dimensional (2D) materials have distinct physical properties and thus are employable in a wide range of device applications [1-9]. Graphene, the first 2D material, has been widely studied since its discovery [3, 10]. It was expected to be a suitable layered structure for the new generation of nanoelectronic devices thanks to its high carrier mobility. However, graphene's zero band gap reminds us that it cannot be effective in many device applications [11-13]. On the other hand, transition metal dichalcogenides (TMDCs) are explored to exhibit tunable band gaps, but on account of practical applications, their relatively low carrier mobilities cannot be neglected [1, 14, 15]. For instance, MoS₂ possesses carrier mobility of approximately 200 cm²V⁻¹s⁻¹ for holes and 72 cm²V⁻¹s⁻¹ for electrons [14], which are much lower in magnitude than that of graphene and even much smaller than Si (480 cm²V⁻¹s⁻¹ for hole and 1350 cm²V⁻¹s⁻¹ for electron) [14, 16]. In recent years, from the fundamental and applicative point of view, we have assisted to tremendous efforts in the investigation of the topological and magnetic properties of the 2D materials and quasi-2D materials [17-25].

Recently, the discovery of novel 2D materials family, XA_2Z_4 (X=Transition metal, A=IV element, Z=V element) [26] has attracted broad consideration due to the outstanding properties they demonstrate. The first member of this assembly is the $MoSi_2N_4$ that was successfully produced via chemical vapor deposition (CVD) process with a large area of size 15 mm \times 15 mm. This semiconducting material with a septuple-atomic-layer configuration (N-Si-N-Mo-N-Si-N) can be regarded as a MoN_2 layer sandwiched in two SiN layers, exhibiting an indirect band gap of almost 1.94 eV. The monolayer of $MoSi_2N_4$ depicts an elastic modulus that is roughly four times larger than MoS_2 , and the carrier mobilities of holes and electrons are also four to six times that of a single layer of MoS_2 . Moreover, a new family, namely XA_2Z_4 (X=Transition metal, A=IV element,

Z=V element) is anticipated by density functional theory (DFT) calculation. So far, several studies have been carried out describing the exceptional features of these materials [27-34].

Designing vertically stacked or laterally stitched two-dimensional heterostructures between 2D materials is an effective technique to unravel new features and extend their applications to electronics, detectors, electroluminescence, and photovoltaics [35-41]. Several experimental techniques such as physical vapor transport, CVD, plasma-assisted deposition, thermal decomposition, and vapor phase growth method have been utilized to synthesize the lateral heterostructures (LH) and vertical heterostructures (VH) [41-47]. Recently, the vertically stacked bilayer of MoSi₂N₄ have been studied using first-principles calculations, which reports the effect of strain on the electronic band gap, the bilayer MoSi₂N₄ showed a decrease in the band gap as the vertical strain was increased; and at around 22% strain, the bilayer revealed a semiconducting to metal transition [31]. Also, the band gap decreases as a function of the electric field for both the MoSi₂N₄, and WSi₂N₄ bilayers, respectively [28]. Likewise, the vertical heterostructures of MoSi₂N₄ and MoGe₂N₄ have been reported, where the electronic properties and ferroelectricity are investigated [29, 30]. Nonetheless, the van der Waals heterostructures of this class are not explored thoroughly and demand a detailed study. In addition, the laterally stitched heterostructures of this novel family are not reported so far.

In this work using first-principle calculations, we carry out a detailed study of XSi₂N₄ (X=Ti, Mo, W) 2D monolayers and their lateral and vertical heterostructures such as TiSi₂N₄/MoSi₂N₄ and MoSi₂N₄/WSi₂N₄. All the compounds are investigated in their 2H crystal structure. The cohesive energies and the absence of imaginary phonon modes in the phonon dispersions exposed the structural stability of XSi₂N₄ systems and their lateral and vertical heterostructures. Since the electronic properties calculated by DFT are usually in poor agreement with the experiments,

principally the band gap, the Hybrid functional (HSE06) is applied to accurately approximate the electronic band structures. Both, the density of states and electronic band structures of XSi₂N₄ 2D materials and their LHs and VHs indicated trivial indirect band gaps. In contrast, a semiconducting to metallic transition is observed in the vertical heterostructure of TiSi₂N₄/MoSi₂N₄. Compared to parent XSi₂N₄ materials, the lateral and vertical heterostructures show the highest free energy and heat capacity values. Our theoretical investigations could pave the path for designing novel nanoelectronic devices based on XSi₂N₄ and their hetero-systems.

2. Methodology

3. Results and discussions

Structural stability

The optimized structures for XSi₂N₄ (X=Ti, Mo, W) monolayers and their heterostructures are visualized in Fig. 1, where the (a), (b) and (c) panels depict the monolayer, lateral heterostructure (LH) and vertical heterostructures (VH), respectively. It can be seen that XSi₂N₄ (X=Ti, Mo, W) possesses a honeycomb structure consisting of Ti/Mo/W, Si and N atoms. The side view illustrates that this structure is stacked by seven atomic layers of N-Si-N-X-N-Si-N that exhibits a sandwich structure of MoN₂ layer by two SiN bilayers. We noticed the optimized lattice constants for XSi₂N₄ (X=Ti, Mo, W) monolayers to be a = b = 2.932, 2.909 and 2.915 Å, respectively. These lattice constants are in perfect agreement with the calculated lattice parameters in the literature [26, 27, 53, 54]. Here, we consider the lateral AA- stitching for the LHs (Fig. 1b) and vertical AB-stacking for the VHs (Fig. 1c), the heterostructures obtained are TiSi₂N₄/MoSi₂N₄-LH, TiSi₂N₄/MoSi₂N₄-VH, MoSi₂N₄/WSi₂N₄-LH, and MoSi₂N₄/WSi₂N₄-VH. In the AA-stacking of VHs, all atoms i.e. the X, Si and N atoms of one monolayer of XSi₂N₄ are located exactly above the X, Si and N atoms of the other XSi₂N₄ layer. Whereas, in AB-stacking, all the atoms in the one XSi₂N₄ layer are staggered with respect to another XSi₂N₄ monolayer, as depicted in Fig. 1c. Based on total ground state energy calculations, the ground state is AB stacking [26, 28, 29].

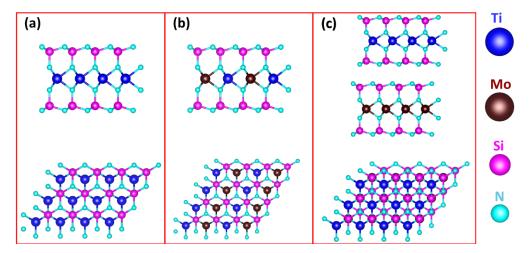


Figure 1 Side and top views of the atomic structures of (a) XSi₂N₄ monolayer, (b) lateral heterostructure (LH), and (c) vertical heterostructure (VH).

In order to check the stability of XSi_2N_4 monolayers and that of LHs and VHs, we used the total ground state energies to compute the cohesive energies. In addition, the phonon dispersions are calculated to determine their dynamical stability, which can enable the use of the studied systems in the device application. In the monolayer case of XSi_2N_4 , the cohesive energy is calculated by [55, 56];

$$E_c = \frac{1E_X + 2E_{Si} + 4E_N - E_{XSi_2N_4}}{1 + 2 + 4}$$

Here, E_X , E_{Si} , E_N and $E_{XSi_2N_4}$ are total ground state energies of isolated X, Si, N atoms and monolayer XSi_2N_4 , respectively. The cohesive energies for $TiSi_2N_4$, $MoSi_2N_4$ and that of WSi_2N_4 are evaluated to be 5.562, 5.589 and 5.653 eV/atom, respectively. By comparing these values with that of graphene (7.46 eV/atom), MoS_2 (4.98 eV/atom) and phosphorene (3.30 eV/atom) [57-59], we noted that they are smaller than graphene but larger than MoS_2 , which indicate the better stability. For the heterostructures, the binding energies are estimated to determine the stability, it is given by [60];

$$E_b = E_{heterostructure} - E_{X^1Si_2N_4} - E_{X^2Si_2N_4}$$

Where $E_{heterostructure}$, denotes the total energy of the heterostructure while $E_{X^1Si_2N_4}$, $E_{X^2Si_2N_4}$ represent the ground state energies of the two monolayers involved in the formation of LH or VH. The binding energies for $TiSi_2N_4/MoSi_2N_4$ -LH, $TiSi_2N_4/MoSi_2N_4$ -VH, $MoSi_2N_4/WSi_2N_4$ -LH, and $MoSi_2N_4/WSi_2N_4$ -VH are -120.175 eV, -45.06 meV, -125.465 eV and -50.082 meV, respectively.

To examine the dynamical stability of XSi₂N₄ (X=Ti, Mo, W) monolayers and that of

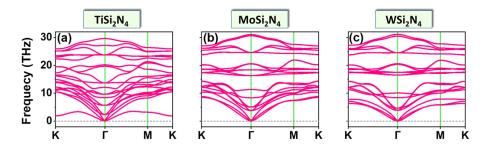


Figure 3 Phonon bandstructures for XSi_2N_4 (X=Ti, Mo, W) monolayers revealing no imaginary modes. heterostructures, we carried out the phonon dispersion calculations as shown in Fig. 2 and 3. The

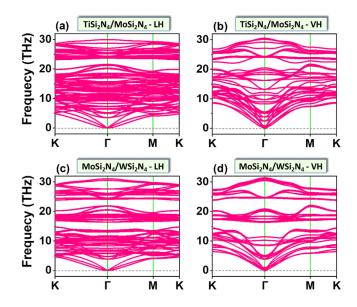


Figure 2 Calculated phonon dispersion curves of the lateral and vertical heterostructures for (a) $TiSi_2N_4/MoSi_2N_4$ -LH, (b) $TiSi_2N_4/MoSi_2N_4$ -VH, (c) $MoSi_2N_4/WSi_2N_4$ -LH and (d) $MoSi_2N_4/WSi_2N_4$ -VH.

finite difference method is employed to calculate the phonon spectra using the Phonopy code [52]

with VASP [61] as a calculator. From the phonon dispersion curves shown in Fig. 2, it is confirmed that all the three XSi₂N₄ (X=Ti, Mo, W) monolayers are dynamically stable due to the absence of imaginary modes. Similarly in Fig. 3, the calculated phonon band spectra along the Brillouin zone's high symmetry directions (K-Γ-M-K) for both the lateral and vertical heterostructures reveal no imaginary frequency at the Γ -point, indicating the dynamical stability of the corresponding systems. Interestingly, the soft acoustic mode of TiSi₂N₄ having a frequency of ~2 THz at the Kpoint (shown in Fig. 2a), becomes harder (increase in the frequency at same wave-vector) when TiSi₂N₄ is brought in combination with any XSi₂N₄ monolayer. This makes TiSi₂N₄ easier to in combination with other compounds. TiSi₂N₄/MoSi₂N₄-LH synthesize For TiSi₂N₄/MoSi₂N₄-VH, the hardening of this mode can be seen in Fig. 3a and 3b, respectively. The hardening of ~2 THz acoustic mode occurring at the K-point can be ascribed to the enhanced coupling at this wave-vector [62, 63].

Electronic properties

To understand the contribution of different orbitals from various elements that characterize our systems' electronic attributes, the total density of states (TDOS) and partial density of states (PDOS) are computed. Figure 4 illustrates the TDOS and PDOS for the respective XSi₂N₄ monolayers. For the monolayer TiSi₂N₄, the valence band maximum (VBM) is mainly dominated by N atoms 'p' orbitals with slight contribution from Ti-d orbitals, while the conduction band minima (CBM) is principally originated by the Ti-d orbital, as illustrated in Fig. 4a. In the case of MoSi₂N₄, and WSi₂N₄, however, both the VBMs and CBMs maximally arise due to the Mo-/W-d orbitals, which are located in the middle of each monolayer structure (Fig. 4b, c).

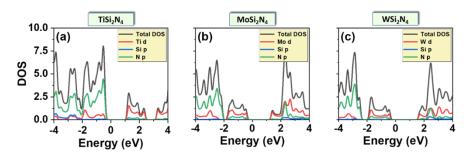


Figure 4 Calculated TDOS and PDOS of (a) $TiSi_2N_4$, (b) $MoSi_2N_4$ and (c) WSi_2N_4 monolayers. The Fermi-level is set to zero energy.

In Fig. 5, we investigate the TDOS and PDOS for the heterostructures including TiSi₂N₄/MoSi₂N₄-UH, TiSi₂N₄/MoSi₂N₄-VH, MoSi₂N₄/WSi₂N₄-LH, and MoSi₂N₄/WSi₂N₄-VH. Figure 5(a), exhibits that the band gap decreases to a very small value of 0.137 eV for TiSi₂N₄/MoSi₂N₄-LH whereby the VBM is dominated by Mo-*d* orbitals with little contributions from N-*p* and Ti-*d* orbitals, whereas the CBM is maximally originated by N-*p* and Ti-*d* orbitals. Interestingly, the TiSi₂N₄/MoSi₂N₄-VH shows metallicity thereby appearing a considerable DOS at the Fermi level as shown in Fig. 5b. This metallic behavior of the VH is mainly contributed by Ti '*d*' orbitals and partly by Mo '*d*' and N '*p*' orbitals. Differently from these two heterostructures of TiSi₂N₄/MoSi₂N₄, the lateral and vertical heterostructures of MoSi₂N₄/WSi₂N₄ manifest large band gaps as shown in Fig. 5c and 5d. For MoSi₂N₄/WSi₂N₄-LH, both the VBM and CBM are dominated mainly by the 'd' orbitals of Mo and W. Similarly, the VBM of MoSi₂N₄/WSi₂N₄-VH maximally arise due to the '*d*' orbitals of Mo and W, while the CBM is contributed by Mo '*d*' orbitals only. In conclusion, all the structures including XSi₂N₄ materials and their heterostructures reveal trivial insulating behavior, except the VH of TiSi₂N₄/MoSi₂N₄, which is metallic.

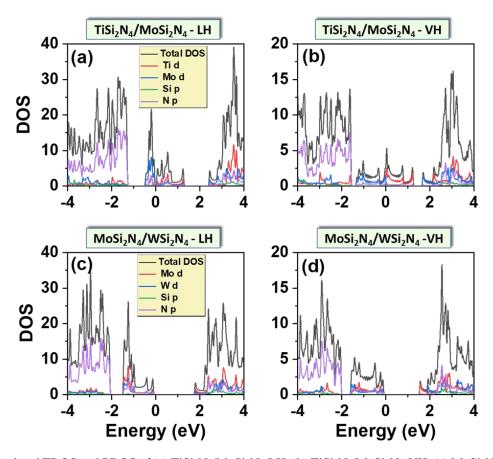


Figure 5 Calculated TDOS and PDOS of (a) TiSi₂N₄/MoSi₂N₄-LH, (b) TiSi₂N₄/MoSi₂N₄-VH, (c) MoSi₂N₄/WSi₂N₄-LH, and (d) MoSi₂N₄/WSi₂N₄-VH. The Fermi-level is set to zero energy.

The electronic band structures were calculated to further investigate the electronic properties of XSi_2N_4 (X=Ti, Mo, W) monolayers and their heterostructures. Since the electronic band gaps calculated by DFT are usually in poor agreement with the experiments and mostly underestimated [64-66], therefore, the Hybrid functional (HSE06) [50] is applied to approximate the electronic band structures. Figure 6 demonstrates the band structures of XSi_2N_4 materials and heterostructures computed through both PBE and HSE06 potentials. The XSi_2N_4 (X=Ti, Mo, W) monolayers possess an indirect band gap of 2.61 eV, 2.35 eV, and 2.69 eV for TiSi₂N₄, MoSi₂N₄, and WSi₂N₄, respectively, as shown in Fig. 6a, b, c. For the TiSi₂N₄/MoSi₂N₄-LH, the maximum of the valence band (VBM) appears at the M-point, while the minimum of the conduction band

(CBM) occurs at the Γ-point (Fig. 6d). On the other hand, in the cases of MoSi₂N₄/WSi₂N₄-LH and MoSi₂N₄/WSi₂N₄-VH, the VBM emerges at Γ-point, whereas the CBM occurs at the K-point, as can be seen in Fig. 6e, f, suggesting that the indirect band gap nature still prevails. The values of the indirect band gaps are determined to be ~0.30, 2.34, and 2.15 eV for the TiSi₂N₄/MoSi₂N₄-LH, MoSi₂N₄/WSi₂N₄-VH, respectively, which could make them promising for the application in solar cells and optoelectronic devices [67-70]. The calculated band gap values are tabulated in Table 1, which are in agreement with the available literature [27, 31, 33]. A slight difference in band gaps may arise due to the difference in lattice parameters.

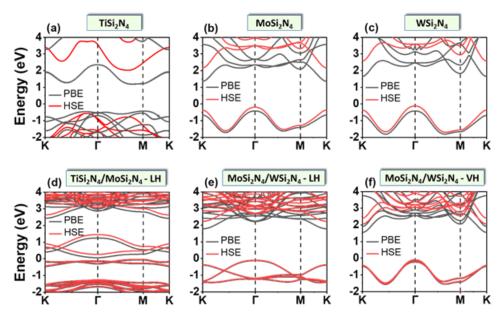


Figure 6 Electronic band structures calculated through PBE (black color) and HSE06 (red color) for (a) $TiSi_2N_4$, (b) $MoSi_2N_4$, (c) WSi_2N_4 , (d) $TiSi_2N_4/MoSi_2N_4$ -LH, (e) $MoSi_2N_4/WSi_2N_4$ -LH and (f) $MoSi_2N_4/WSi_2N_4$ -VH.

Table 1 Calculated electronic band gaps of XSi_2N_4 materials and their lateral and vertical heterostructures using PBE and HSE06.

Material	PBE Band gap (eV)	HSE Band gap (eV)
TiSi ₂ N ₄	1.63	2.40
$MoSi_2N_4$	1.74	2.35
WSi_2N_4	2.12	2.60
$TiSi_2N_4/\ MoSi_2N_4-LH$	0.14	0.30
$MoSi_2N_4/WSi_2N_4-LH$	1.90	2.34
$MoSi_2N_4/WSi_2N_4-VH$	1.70	2.15

Thermal properties

Based on the stable phonon dispersions of XSi_2N_4 (X=Ti, Mo, W) monolayers and their heterostructures, the thermal characteristics including entropy (S), Helmholtz free energy (F), and heat capacity C_v are calculated as shown in Figure 7. The entropy of all the systems rises steadily with the temperature, consistently with the fact that increasing the temperature gives rise to several microstates in the system W, which results in an increase in the entropy logarithmically according to the Boltzmann's entropy formula ($S = k_B log W$, where k_B is the Boltzmann constant). On the other hand, the Helmholtz free energy, F, is observed to decline with temperature, as shown in Fig. 7b and 7e, which agrees with F(T) = U(T) - TS(T); U(T) is the lattice internal energy. Furthermore, we investigate the heat capacity C_v of XSi_2N_4 (X=Ti, F0, F1) monolayers and their heterostructures as a function of temperature as illustrated in Fig. 7c and 7f. Comparable heat capacities of $TiSi_2N_4$, $MoSi_2N_4$ and WSi_2N_4 are observed as reported in Fig. 7c and 7f.

Intriguingly, the heat capacity increases for the VHs and further enhances for the LHs. At room temperature, the C_v values are estimated to be 106.1, 100.5, 100.8, 206.5, 415.6, 201.3 and 402.3 JK⁻¹mol $^{-1}$ for TiSi₂N₄, MoSi₂N₄, WSi₂N₄, TiSi₂N₄/MoSi₂N₄-VH, TiSi₂N₄/MoSi₂N₄-LH, MoSi₂N₄/WSi₂N₄-VH and MoSi₂N₄/WSi₂N₄-LH, respectively. Our estimated values of C_v are relatively higher than PbSe and PbTe [71, 72] (which are thought to be excellent thermoelectric materials), suggesting the better ability of XSi₂N₄ (X=Ti, Mo, W) monolayers and their heterostructures to retain heat. The heat capacity of XSi₂N₄ (X=Ti, Mo, W) monolayers takes the lead to approach the Dulong-petit asymptotic value (i.e. $C_v = 3NR$, where N is the number of atoms and R is the universal gas constant) at around T ~560 K. Whereas, the VHs of TiSi₂N₄/MoSi₂N₄, and MoSi₂N₄/WSi₂N₄ approach this asymptote at a relatively higher temperature, near T ~650 K, and LHs of TiSi₂N₄/MoSi₂N₄, and MoSi₂N₄/WSi₂N₄ required a higher temperature of around T~750 K and T~850K to approach this value. From this investigation, we found that C_v is consistent with the entropy we computed here since the variation of entropy corresponds to the integral of (C_v/T) over a given temperature range.

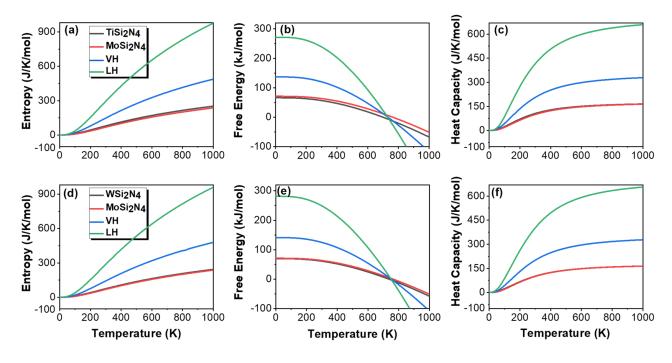


Figure 7 Thermal properties such as entropy, free energy and heat capacity. The top panels (a), (b) and (c) represent $TiSi_2N_4$, $MoSi_2N_4$ and their lateral and vertical heterostructures, while the lower panel characterizes $MoSi_2N_4$, WSi_2N_4 , and their lateral and vertical heterostructures.

4. Conclusions

The structural stability, electronic properties and thermal characteristics of XSi₂N₄ (X= Ti, Mo, W) monolayers and their lateral and vertical heterostructures are explored using density functional theory. We noticed that interfacing two different 2D structures either laterally or vertically, significantly tunes the physical properties of the parent 2D monolayers that may have technological impact in many potential applications. The structural stability of these systems was confirmed by the cohesive energies which are based on the total ground state energies and the phonon dispersions revealing the dynamical stability. Apart from their stability, our results illustrated that the lateral and vertical heterostructures present outstanding electronic and thermal features. All the three monolayers i.e. TiSi₂N₄, MoSi₂N₄, and WSi₂N₄ revealed indirect band gaps. Remarkably, a semiconducting to metallic transition is observed in the VH of TiSi₂N₄/MoSi₂N₄,

while the LH of $TiSi_2N_4/MoSi_2N_4$ manifested a small band gap. Both the lateral and vertical heterostructures of $MoSi_2N_4/WSi_2N_4$ revealed semiconducting nature with modifications in their band gaps with respect to the parent monolayers. Compared to the transition metal dichalcogenides, the monolayers XSi_2N_4 and their heterostructures bear the highest values for the free energy and heat capacity. The study suggests that both the XSi_2N_4 2D monolayers and their heterostructures could be promising in the next-generation optoelectronics and nanoelectronics.

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